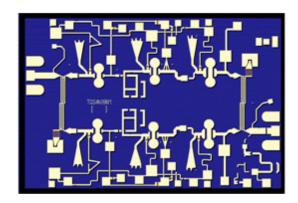


Product Data Sheet August 5, 2008

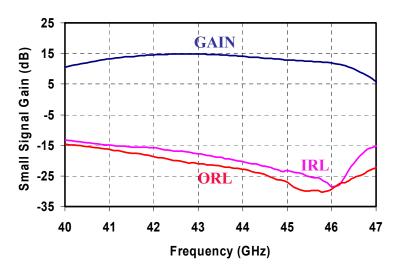
TGA4042

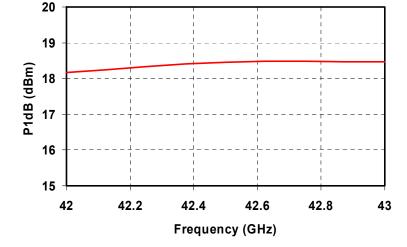
Q-Band Driver Amplifier



Preliminary Measured Data

Bias Conditions: Vd = 6 V, Id = 168 mA





Note: Datasheet is subject to change without notice.

Key Features

- Typical Frequency Range: 41 45 GHz
- 18 dBm Nominal P1dB
- 14 dB Nominal Gain
- 17 dB Nominal Return Loss
- On-Chip Power Detector
- Bias 6 V, 168 mA
- 0.25 um 2MI pHEMT Technology
- Chip Dimensions 3.20 x 2.18 x 0.1 mm $(0.126 \times 0.086 \times 0.004)$ in

Primary Applications

- Point-to-Point Radio
- Military Radar Systems
- Q Band Sat-Com

Product Data Sheet August 5, 2008

TGA4042

TABLE I MAXIMUM RATINGS 1/

SYMBOL	PARAMETER	VALUE	NOTES
Vd	Drain Voltage	8 V	<u>2/</u>
Vg	Gate Voltage Range	-5 TO 0 V	
ld	Drain Current	294 mA	<u>2</u> / <u>3</u> /
Ig	Gate Current	14 mA	<u>3</u> /
P_{IN}	Input Continuous Wave Power	21 dBm	
P_{D}	Power Dissipation	3.3 W	<u>2</u> / <u>4</u> /
T _{CH}	Operating Channel Temperature	150 ⁰ C	<u>5</u> / <u>6</u> /
T_M	Mounting Temperature (30 Seconds)	320 °C	·
T _{STG}	Storage Temperature	-65 to 150 °C	

- 1/ These ratings represent the maximum operable values for this device.
- 2/ Combinations of supply voltage, supply current, input power, and output power shall not exceed P_D.
- 3/ Total current for the entire MMIC.
- 4/ When operated at this bias condition with a base plate temperature of 70 °C, the median life is reduced to 1E+6 hrs.
- 5/ Junction operating temperature will directly affect the device median time to failure (MTTF). For maximum life, it is recommended that junction temperatures be maintained at the lowest possible levels.
- 6/ These ratings apply to each individual FET.

TABLE II DC PROBE TESTS

 $(Ta = 25 \, {}^{\circ}C, Nominal)$

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNITS
I _{DSS,Q1}	Saturated Drain Current	20	57	94	mA
$G_{M,Q1}$	Transconductance	44	75	106	mS
V _{BVGS,Q1}	Breakdown Voltage Gate-Source	-30	-21	-8	V
V _{BVGD,Q1} & Q3	Breakdown Voltage Gate-Drain	-30	-21	-8	V
V _{P,Q1-Q6}	Pinch-Off Voltage	-1.5	-1	-0.5	V

Q1& Q2 are 200 um FETs, Q3 & Q4 are 240 um FETs, Q5 & Q6 are 400 um FETs



Product Data Sheet August 5, 2008 **TGA4042**

TABLE III ELECTRICAL CHARACTERISTICS

(Ta = 25 °C, Nominal)

PARAMETER	TYPICAL	UNITS
Frequency Range	41 - 45	GHz
Drain Voltage, Vd	6	V
Drain Current, Id	168	mA
Gate Voltage, Vg	-0.5	V
Small Signal Gain, S21	14	dB
Input Return Loss, S11	17	dB
Output Return Loss, S22	20	dB
Output Power @ 1 dB Compression Gain, P1dB	18	dBm

TABLE IV THERMAL INFORMATION

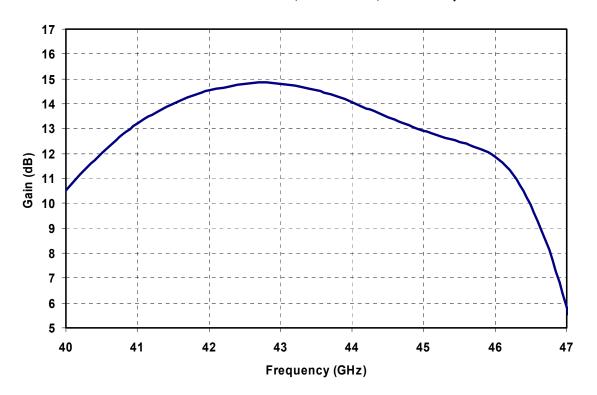
PARAMETER	TEST	T _{сн}	R _{θJC}	T _M
	CONDITIONS	(^o C)	(°C/W)	(HRS)
R _{θJC} Thermal Resistance (channel to backside of carrier)	$Vd = 6 V$ $I_D = 168 \text{ mA}$ $Pdiss = 1.008 W$	92.58	22.40	2.7E+8

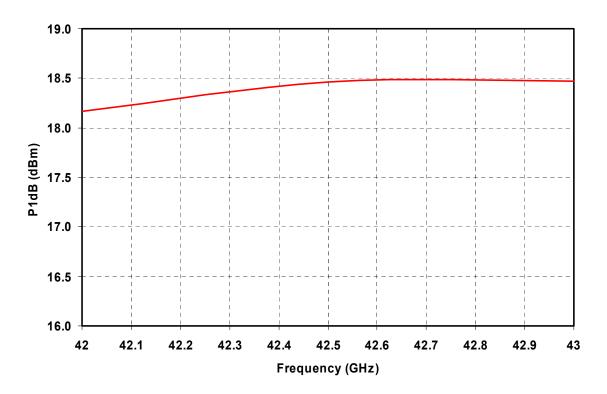
Note: Assumes eutectic attach using 1.5 mil 80/20 AuSn mounted to a 20 mil CuMo Carrier at 70°C baseplate temperature. Worst case condition with no RF applied, 100% of DC power is dissipated.



Preliminary Measured Data

Bias Conditions: Vd = 6 V, Id = 168 mA, Room Temp.



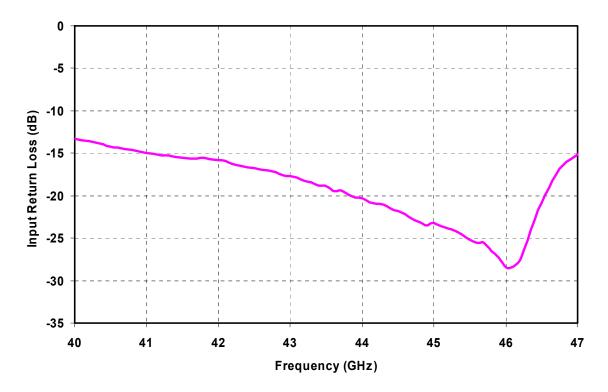


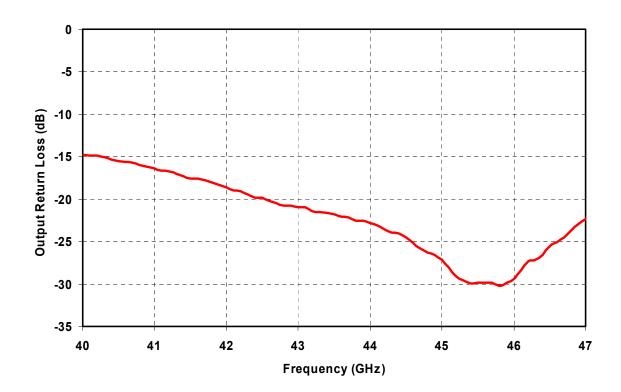




Preliminary Measured Data

Bias Conditions: Vd = 6 V, Id = 168 mA, Room Temp.

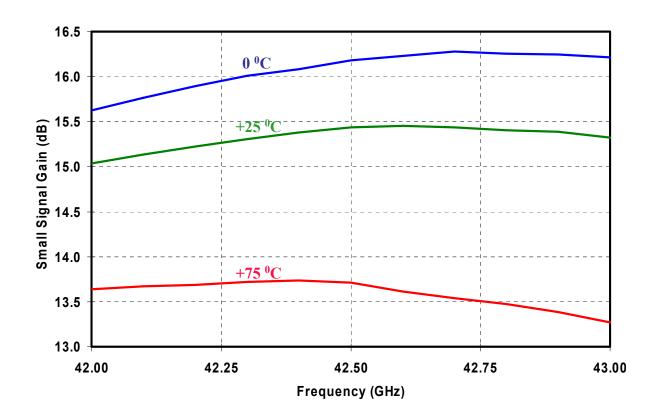






Preliminary Measured Data

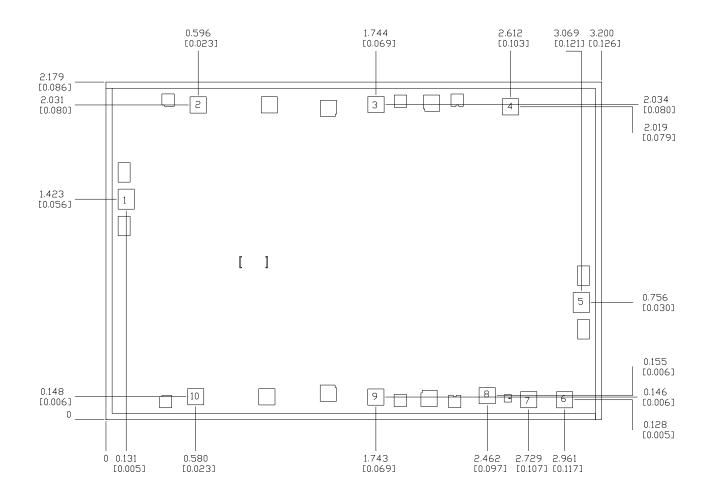
Bias Conditions: Vd = 6 V, Id = 168 mA







Mechanical Drawing

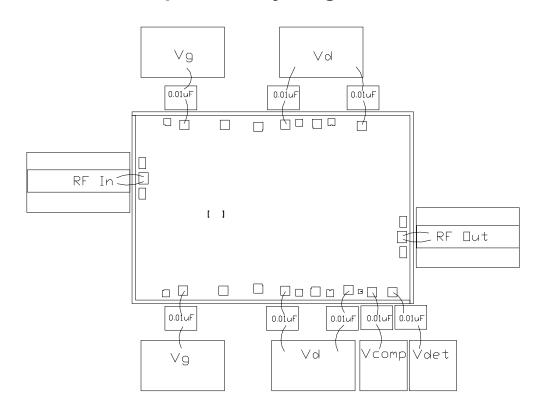


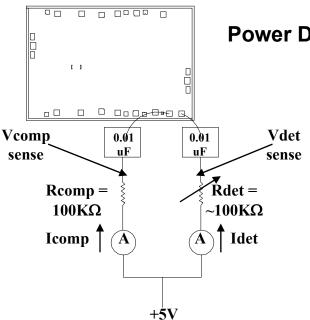
```
Units: Millimeters (inches)
Thickness: 0.100 (0.004) (reference only)
Chip edge to bond pad dimensions are shown to center of bond pad
Chip size tolerance: +/- 0.051 (0.002)
RF Ground is backside of MMIC
                               (RF Input)
                                                0.105 \times 0.130
                                                               (0.004 \times 0.005)
Bond pad #1
                                                0.105 \times 0.105
                                                               (0.004 \times 0.004)
Bond pad #2 & #10
                               (Vg)
                               (Vď)
                                                0.105 \times 0.105
                                                               (0.004 \times 0.004)
Bond pad #3, #4, #8, #9
Bond pad #5
                               (RF Dutput)
                                                0.105 \times 0.130
                                                               (0.004 \times 0.005)
                               (Vdet)
                                                0.105 \times 0.105
                                                               (0.004 \times 0.004)
Bond pad #6
                                                0.105 \times 0.105
                                                               (0.004 \times 0.004)
                               (Vcomp)
Bond pad #7
```

GaAs MMIC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.



Chip Assembly Diagram





Power Detector Bias Circuit

Note:

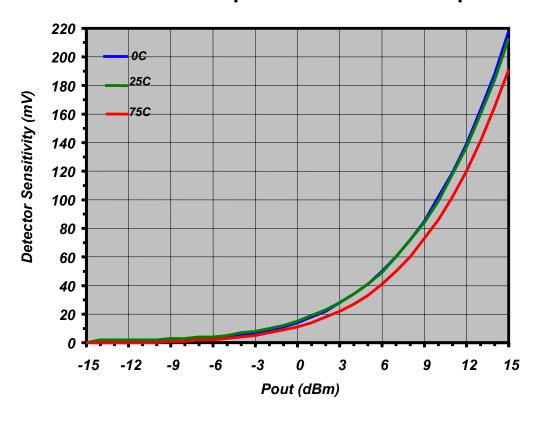
- 1. With no RF power applied, adjust Rdet until Idet = Icomp (approx 41uA) and record Vdet.
- 2. Record Vdet as Pout increases.

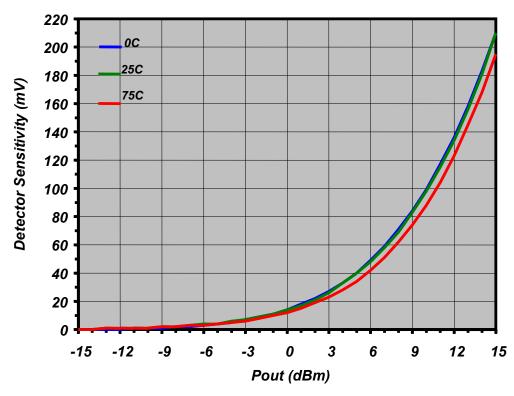
 Detector sensitivity at a particular Pout is defined as delta between Vdet at Pout of interest and Vdet with no Pout.

GaAs MMIC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.



Power Detector performance over temperature







Product Data Sheet August 5, 2008 **TGA4042**

Assembly Process Notes

Reflow process assembly notes:

- Use AuSn (80/20) solder with limited exposure to temperatures at or above 300°C (30 seconds max).
- An alloy station or conveyor furnace with reducing atmosphere should be used.
- No fluxes should be utilized.
- Coefficient of thermal expansion matching is critical for long-term reliability.
- Devices must be stored in a dry nitrogen atmosphere.

Component placement and adhesive attachment assembly notes:

- Vacuum pencils and/or vacuum collets are the preferred method of pick up.
- Air bridges must be avoided during placement.
- The force impact is critical during auto placement.
- Organic attachment can be used in low-power applications.
- Curing should be done in a convection oven; proper exhaust is a safety concern.
- Microwave or radiant curing should not be used because of differential heating.
- Coefficient of thermal expansion matching is critical.

Interconnect process assembly notes:

- Thermosonic ball bonding is the preferred interconnect technique.
- Force, time, and ultrasonics are critical parameters.
- Aluminum wire should not be used.
- Maximum stage temperature is 200 °C.

GaAs MMIC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.

X-ON Electronics

Largest Supplier of Electrical and Electronic Components

Click to view similar products for RF Amplifier category:

Click to view products by Qorvo manufacturer:

Other Similar products are found below:

A82-1 BGA622H6820XTSA1 BGA 728L7 E6327 BGB719N7ESDE6327XTMA1 HMC397-SX HMC405 HMC561-SX HMC8120-SX HMC8121-SX HMC-ALH382-SX HMC-ALH476-SX SE2433T-R SMA3101-TL-E SMA39 A66-1 A66-3 A67-1 LX5535LQ LX5540LL MAAM02350 HMC3653LP3BETR HMC549MS8GETR HMC-ALH435-SX SMA101 SMA32 SMA411 SMA531 SST12LP17E-XX8E SST12LP19E-QX6E WPM0510A HMC5929LS6TR HMC5879LS7TR HMC1126 HMC1087F10 HMC1086 HMC1016 SMA1212 MAX2689EWS+T MAAMSS0041TR MAAM37000-A1G LTC6430AIUF-15#PBF CHA5115-QDG SMA70-2 SMA4011 A231 HMC-AUH232 LX5511LQ LX5511LQ-TR HMC7441-SX HMC-ALH310